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 Kunikiyo, T.; Watanabe, T.; Kanamoto, T.; Asazato, H.; Shirota, M.; Eikyu, K.; Makino, H.; Ishikawa, K.; Iwade, S.; Inoue, Y.;  
 Electron Devices, IEEE Transactions on  
 Volume 51, Issue 5, May 2004 Page(s):726 - 735  
 Digital Object Identifier 10.1109/TED.2004.826899  
[AbstractPlus](#) | Full Text: [PDF](#)(672 KB) IEEE JNL
- ☐ 2. **Non-destructive inverse modeling of copper interconnect structure for 90 node**  
 Kunikiyo, T.; Watanabe, T.; Kanamoto, T.; Asazato, H.; Shirota, M.; Eikyu, K.; Makino, H.; Ishikawa, K.; Iwade, S.; Inoue, Y.; Yamashita, K.; Kobayashi, M.; C Y.; Yamaguchi, R.; Umimoto, H.; Ohtani, K.;  
 Simulation of Semiconductor Processes and Devices, 2003. SISPAD 2003. Int Conference on  
 3-5 Sept. 2003 Page(s):31 - 34  
 Digital Object Identifier 10.1109/SISPAD.2003.1233630  
[AbstractPlus](#) | Full Text: [PDF](#)(374 KB) IEEE CNF
- ☐ 3. **A high performance 1.5 V, 0.10  $\mu$ m gate length CMOS technology with sc: metallization**  
 Gilbert, P.; Yang, I.; Pettinato, C.; Angyal, M.; Boeck, B.; Fu, C.; VanGompel, T Sparks, T.; Clark, W.; Dang, C.; Mendonca, J.; Chu, B.; Lucas, K.; Kling, M.; R E.; Huang, F.; Woods, M.; Rose, D.; McGuffin, K.; Nghiem, A.; Banks, E.; McN Sturtevant, J.; De, H.; Das, A.; Veeraraghavan, S.; Nkansah, F.; Bhat, M.;  
 Electron Devices Meeting, 1998. IEDM '98 Technical Digest., International  
 6-9 Dec. 1998 Page(s):1013 - 1016  
 Digital Object Identifier 10.1109/IEDM.1998.746526  
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